

## **Advances in Nanoscale Analysis of Hf Doped Nb<sub>3</sub>Sn Wires Using Atom Probe Tomography**

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**Abstract** — The Future Circular Collider (FCC) will require Nb<sub>3</sub>Sn dipole magnets that can operate up to 16 T [1], however, achieving this demanding specification will require conductors with an exceptionally high critical current density (J<sub>c</sub>) of 1500 Am<sup>-2</sup> whilst maintaining a residual resistivity ratio (RRR) of 150. Despite a great deal of research into new manufacturing techniques and heat treatments for Nb<sub>3</sub>Sn wires, it remains a very challenging and ambitious target. All commercial Nb<sub>3</sub>Sn strands use Ta and/or Ti doping for high field performance but in this study, we look at the impact of also adding Hf, which has been shown to increase flux-pinning and thus may help Nb<sub>3</sub>Sn wires reach the FCC target specifications. To determine how Hf affects the superconducting properties of the Nb<sub>3</sub>Sn it is important to use a nanoscale microscopy technique to visualize how the Hf is modifying the Nb<sub>3</sub>Sn layer. This study uses Atom Probe Tomography (APT) to locate secondary phases, segregation at grain boundaries and discusses the origin of O in the sample.

**Keywords (Index Terms)** –Future circular collider, critical current, pinning force, atom probe tomography, backscattered detector, transmission electron microscopy, electron probe microanalyser, energy dispersive x-ray spectroscopy

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